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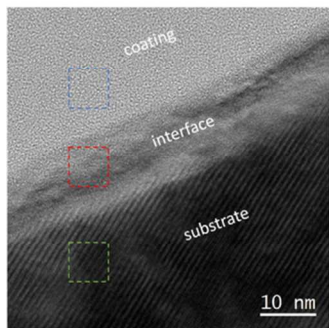
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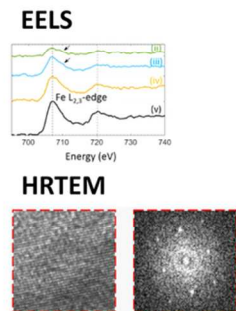


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**Investigation of bonding
in SOG/substrate interface**



**Characterization by
TEM**



**Discussion of bonding
mechanism**

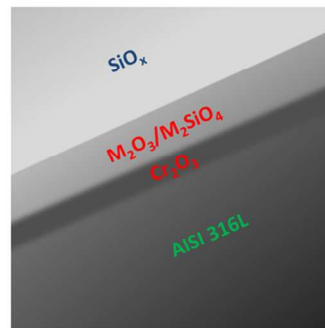


Table of Contents/Abstract Graphic

87x38mm (300 x 300 DPI)

Probing the chemistry of adhesion between a 316L substrate and spin-on-glass coating

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Abstract

Hydrogen silsesquioxane ($[\text{HSiO}_{3/2}]_n$) based “spin-on-glass” has been deposited on 316L substrate and cured in Ar/H₂ gas atmosphere at 600 °C to form a continuous surface coating with sub-micrometer thickness. The coating functionality depends primarily on the adhesion to the substrate, which is largely affected by the chemical interaction at the interface between the coating and the substrate. We have investigated this interface by transmission electron microscopy and electron energy loss spectroscopy. The analysis identified a 5-10 nm thick interaction zone containing signals from O, Si, Cr and Fe. Analysis of the energy loss near edge structure of the present elements identified predominantly signal from $[\text{SiO}_4]^{4-}$ units together with Fe^{2+} , Cr^{2+} and traces of Cr^{3+} . High-resolution transmission electron microscopy images of the interface region confirm a crystalline Fe_2SiO_4 interfacial region. In agreement with computational thermodynamics, it is proposed that the spin-on-glass forms a chemically bonded silicate-rich interaction zone with the substrate. It was further suggested that this zone is composed of a corundum-type oxide at the substrate surface, followed by an olivine-

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3 structure intermediate phase and a spinel-type oxide in the outer regions of the interfacial
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5 zone.
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9 **1 Introduction**

11 Due to their inherent resistance towards galvanic corrosion combined with good formability,
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13 austenitic stainless steels belong to the most widely used engineering materials. Apart from
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15 the chemical composition and the mechanical/thermal history, the functionality of the
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17 materials is greatly determined by the surface finish, and hence their surface modification
18
19 plays a major role in the development of improved stainless steel engineering components.
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21 Over the recent years, intense research effort has been directed into the surface modification
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23 by SiO_x-based micrometer/sub-micrometer thick coatings to improve the wear resistance^{1,2},
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25 biocompatibility^{3,4}, bio fouling characteristics and cleanability^{5,6}, surface morphology⁷⁻¹⁰ and
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27 corrosion resistance in saline¹¹⁻¹³, acid^{11,14,15} or high temperature¹⁶ environments of stainless
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29 steel components at a minimal impact on the component geometry. Apart from the traditional
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31 deposition processes, such as chemical vapor deposition¹⁷, physical vapor deposition¹⁸, sol-gel
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33 processing¹⁹ or liquid phase deposition²⁰, the deposition from hydrogen silsesquioxane
34
35 (HSQ), [HSiO_{3/2}]_n, spin-on-glass (SOG) has shown excellent results for the processing of high
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37 quality SiO_x-like thin films^{21,22}. In addition to the deposition of near stoichiometric silica
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39 films, SOG-technology offers the possibility to deposit fully inorganic films with various
40
41 degrees hydrogenation as intermediate reaction products, resulting in a broad range of film
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43 properties²¹⁻²³. While the material was mainly developed for microelectronics applications^{23,24}
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45 or as electron beam resist²⁵, it has recently emerged into the surface finishing industry and
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47 shown an outstanding performance as coating material for metallic substrates such as
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49 aluminum or tool steel⁷⁻¹⁰.
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3 Recently, we have shown the applicability of SOG as material for sub-micrometer thick
4 coatings on stainless steel substrates^{26–28}. Our studies have proven the concept of precursor
5 deposition by an industrially applicable dip-coating process and the subsequent coating curing
6 in both oxidizing^{27,28} and non-oxidizing²⁶ atmosphere, showing that both processes may yield
7 well adherent coatings with 200-400 nm thickness on substrates with 2B finish²⁹; however,
8 we have also demonstrated that the coating efficiently levels the substrate surface, and thus
9 fills substrate defects (e.g. surface voids), which may consequently lead to a local increase in
10 coating thickness exceeding 1400 nm²⁶. Further, we have shown that oxidative curing induces
11 thermal oxidation of the substrate²⁷, leading to adhesive failure of the coating and ultimately
12 to functional component failure²⁸. We have reported that the formation of a thick, detrimental
13 interface was driven by an abundance of oxygen in the curing atmosphere²⁷, and that the
14 formation of a thick interfacial zone can be suppressed by a removal of oxygen from the
15 curing atmosphere, i.e. by curing in a non-oxidizing atmosphere such as Formiergas²⁶.
16 However, the methods applied in the previous work were inadequate to clearly resolve the
17 interface between the coating and the substrate and, hence, the interfacial chemistry,
18 morphology and the bonding mechanism between coating and substrate are unclear.

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38 In agreement with other studies^{11,13,30–35}, our previous findings^{27,28} emphasize the significance
39 of the coating/substrate interface for both the adhesion and the performance of glass coatings
40 on stainless steel. However, to the author's knowledge, previous studies have generally
41 focused on the formation of thick interface oxides^{31–33}, traditional enameling technology of
42 complex industrial porcelains³⁰ or on vapor deposition techniques^{34,35}, which may lead to
43 significantly different bonding mechanisms. Consequently, the interface formation of well
44 adherent, non-oxidatively cured HSQ-based coatings cannot be adequately deduced based on
45 previous literature. Hence, the present study aims at a detailed characterization of the
46 interfacial chemistry of non-oxidatively cured SOG on type 316L substrate by Transmission
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3 Electron Microscopy (TEM). The interface was characterized by electron energy loss
4 spectroscopy in scanning-TEM together with and high resolution TEM and the analytical
5 results are discussed based on the thermodynamical oxide/metal phase equilibrium at the
6 interface. This analysis provides novel insights into the metal-glass bonding mechanism of
7 silica-like coatings on stainless steel substrate and, in conclusion, the adhesive performance of
8 the coatings.
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18 **2 Experimental section**

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20 To analyze the bonding mechanism between a stainless steel substrate and a SOG coating,
21 AISI 316L substrates (composition in Table I) with no. 2B surface finish were coated with
22 HSQ-based SOG by the method previously described in Lampert *et al.*²⁶: The test coupons
23 were dip coated in commercial HSQ-solution (Dow Corning FOx 25) and subjected to a two
24 stage heat treatment, the first step being a soft bake at 160 °C in air and the second a
25 polymerization at 600 °C under flow of 0.5 l/min Ar/H₂ gas mixture (10 vol.% H₂) for 2h. The
26 temperature of the polymerization stage was elevated with respect to our previous work²⁶ in
27 order to decrease the susceptibility of the coating material to ionizing irradiation³⁶ during ion
28 beam milling and the TEM investigation.
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40 Lamellae for TEM investigations were prepared by focused ion beam (FIB) milling in a FEI
41 Helios NanoLab 600 dual beam scanning electron microscope (SEM). The specimens were
42 first sputter coated with 20-30 nm of Au to avoid surface charging during the FIB preparation,
43 followed by in-situ deposition of a Pt layer prior to milling to protect the sample from
44 irradiation damage. FIB-milling was carried out at 30 kV ion beam accelerating voltage,
45 followed by final polishing at 2 kV ion beam accelerating voltage and 0.44 nA ion beam
46 current. The lamellae were additionally polished in a Fischione NanoMill precision Ar-ion
47 mill (500 V accelerating voltage and 100 pA beam current) to remove the residual FIB
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3 damage. The TEM examination of the samples was performed in a FEI Titan 80-300kV
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5 instrument fitted with a FEG electron source, a monochromator and a GIF Tridiem electron
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7 energy loss spectroscopy (EELS) spectrometer. Scanning-TEM (STEM) -EELS
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9 measurements were carried out at 120 kV accelerating voltage. In STEM, spatial resolutions
10
11 of 5 Å and 1.5 Å, respectively with and without the monochromator excited, were obtained.
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13 The EELS measurements were acquired with the monochromator excited and had an energy
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15 resolution of 0.15 eV. High-resolution TEM (HRTEM) imaging was carried out at 300 kV
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17 and with the point to point resolution of 1.4 Å. Thermodynamic phase equilibrium
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19 calculations were performed in Thermo-Calc version 2017a³⁷ using version 7.0 of the
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21 Thermo-Calc Software steel database TCFE. The elements Fe, Cr, Mn, Ni, Si and O were
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23 considered in the calculations.
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28 **3 Results and Discussion**

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31 A high-angle annular dark-field (HAADF) STEM image of the coating – substrate cross-
32
33 section is shown in Figure 1(a). Image intensity in HAADF STEM is primarily related to the
34
35 atomic number (Z-contrast) of the material, indicating an interfacial region distinct from the
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37 coating and the substrate (labelled “interface”). This is similar to our previous investigation of
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39 an oxidatively cured coating²⁷, where an interfacial reaction zone was detected. Here, a much
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41 thinner interfacial zone of 5 – 10 nm is detected, compared to in the oxidatively cured coating.
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43 EELS line scans spanning energy ranges 400 – 1000 eV (covering the O K-edge and Cr, Mn,
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45 Fe and Ni L_{2,3}-edges) and 90 – 150 eV (containing the Si L_{2,3}-edge) were acquired from the
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47 coating/substrate interface, in order to probe the chemistry of this interfacial zone. The Si L_{2,3}-
48
49 edge had to be recorded separately, as our experimental setup limits the spectral energy range
50
51 to 600 eV at most, and thus we were unable to record all edges of interest together in the same
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53 spectrum. The relative composition profile of O, Cr and Fe calculated from the EEL spectra
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55 along with the HAADF intensity profile and the intensity of the Si signal along a line across
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3 the interface are plotted in Figure 1(b). Approximate boundaries for the substrate and the
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5 coating, determined from the changes in the HAADF image intensity profile along the
6
7 recorded line scans, are marked in the graphs. We were unable to analyze the composition
8
9 profile of Ni, due to the pronounced overlap between the Ni L_{2,3}-edge and the Fe L₁-edge. The
10
11 detection of the Mn L_{2,3}-edge was also hindered due to its low concentration and low signal
12
13 level in the measurements. The measurements were repeated across different regions of the
14
15 sample and were found to be reproducible. As evident in the graphs in Figure 1(b) the
16
17 constituent elements have relatively unchanged concentrations in the substrate and the
18
19 coating. An interfacial zone of approximately 6 nm, containing all four elements Fe, Cr, O
20
21 and Si is detected. The concentrations of Fe and Cr in the interface decrease from the
22
23 substrate towards the coating and those of O and Si increase.
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27 The energy-loss near-edge fine-structure (ELNES) in EELS is a powerful tool in probing the
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29 local chemistry of a sample, containing information such as chemical bonding, oxidation
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31 state, crystal structure and coordination³⁸. EEL spectra recorded at different points along the
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33 interface are plotted in Figure 2(a) (O, Cr, Fe) and Figure 2(b) (Si). Here we analyze the
34
35 ELNES of the spectra in different regions:
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39 **Coating.** The signal acquired in the coating contains the Si L- and the O K-edges. The
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41 ELNES in both the Si L_{2,3}- and O K-edges in this region (spectra at position (i)) resemble
42
43 closely those for amorphous SiO₂ with SiO₄ tetrahedral networks³⁹⁻⁴¹: the Si L_{2,3}-edge
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45 contains three main peaks at ~ 106 eV, ~ 108 eV and ~ 115 eV. The first peak corresponds to
46
47 2p to unoccupied s-type states in Si and its onset has been shown to vary from ~ 100 eV for
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49 Si⁰ to ~ 103 eV for Si²⁺ to ~ 105 eV for Si⁴⁺⁴². The peaks at 108 eV and 115 eV arise from 2p
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51 to dominantly d-type states, and are influenced by the Si – O tetrahedral coordination in
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53 silica^{39,40}. The O K-edge in the coating features a main peak at ~ 537 eV and a broad peak at ~
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55 560 eV.
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3 **Interface.** The spectra acquired in the interface contains signals from Si, O, Cr and Fe. Little
4 change is observed in the fine structure of Si L_{2,3}-edge at position (ii) in the interface relative
5 to the coating. This indicates the continued dominant presence of [SiO₄]⁴⁻ units in the
6 interface. The splitting in the initial peak at 106 eV, due to spin-orbit coupling of 2p electrons
7 in Si, can be clearly resolved here^{41,43}. A pre-peak at ~ 103 eV appears in the spectra at
8 positions (iii) and (iv). The reduced onset energy of the Si L_{2,3} edge signifies a lower
9 oxidation number of Si at these positions, which may be related to the presence of Fe and Cr
10 in the interface, *e.g.* due to the formation of olivine (Me₂SiO₄)-structure phases such as
11 Fe₂SiO₄³⁹ or Cr-bearing Si sub-oxides⁴⁰. The O K-edges from positions (ii) and (iii) have
12 overall similar profiles to that acquired in the coating. The first peak at ~ 537 eV arises
13 mainly from scattering of excited electrons (from 1s state in O) by second nearest O neighbors
14 and beyond⁴⁴ and has been shown to have little dependence on *e.g.* the Si – O – Si bond
15 angle^{45,46}. The peak at ~ 560 eV has been shown to shift to lower energies with increasing Si –
16 O bond length (*i.e.* reduced ionic character)⁴⁴. Such a shift is observed in the O K-edge at
17 position (ii) and (iii). Additionally, the peak at ~ 537 eV in the spectra acquired at positions
18 (ii), (iii) and (iv) contains a shoulder on the right hand side, indicating a larger crystal field
19 effect⁴⁷ compared to position (i). This could be the result of distortion or change in the
20 structure of the interface relative to the coating. A decrease in the onset energy of the O K-
21 edge and a hint of a pre-peak can be seen in the spectra at positions (iii) and (iv). A pre-peak
22 is typically present in the ELNES of the O K-edge of transition metal oxides^{48,49} and a similar
23 decrease in onset energy of the O K-edge can be observed for silicates such as Fe₂SiO₄
24 (fayalite)⁵⁰. The L_{2,3} edges of transition metals reveal valuable information regarding their
25 oxidation state, crystal structure and chemical environment. For example, the position of the
26 L₂ and L₃ peaks are shown to be sensitive to their oxidation and shift typically to higher
27 energies with increasing oxidation state^{49,51–54}. The intensity ratio of L₃/L₂ edges in transition
28 metals is another important parameter related to the d-orbital occupancy (and subsequently
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3 the oxidation state). Each of the L_2 and L_3 peaks can also contain fine details, stemming from
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5 crystal field effects, which provide further clues to the chemical state of the transition
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7 metal^{49,51,54}. The peak maxima of the Fe L_3 and L_2 here are positioned respectively at ~ 707
8
9 eV and ~ 720 eV, without showing any noticeable change across the interface (see spectra (ii)
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11 – (iv)). The average integrated intensity of L_3/L_2 edges of Fe in the interface region
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13 determined according to the method described by van Aken *et al.*⁴⁷ is 3.5 (L_3/L_2 ratio in the
14
15 substrate is ~ 2.8). Both the peak maxima energies and the L_3/L_2 ratio in the interface region
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17 correspond well to those for Fe^{2+} ^{47,49,51,55}. The fine structure present on the Fe $L_{2,3}$ edge
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19 across the interface is also consistent with this observation: A splitting in the L_3 edge (marked
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21 with arrows in spectra (ii) and (iii) of Fe $L_{2,3}$ edges in Figure 2(a)) can be resolved,
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23 characterized by a small bump at ~ 710 eV after the main peak^{47,49,51}. We thus conclude that
24
25 the Fe present in the interface region is predominantly in Fe^{2+} state. In the case of Cr, small
26
27 shifts in the L_3 peak maxima at different points across the interface are detected. The
28
29 measured L_3 and L_2 peak maxima at position (iii) of ~ 576 eV and ~ 585 eV correspond
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31 closely to Cr^{2+} ^{52,54}. Although the fine structure on the Cr L_3 edge cannot be clearly resolved
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33 in our measurements, its overall profile at position (iii) also suggests the presence of Cr^{2+} ^{52,54}.
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35 In comparison, the Cr L_3 peaks at positions (ii) and (iv) have their maxima at slightly higher
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37 energies (approximately 1.0 eV and 0.6 eV shifts at positions (ii) and (iv), respectively). Their
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39 overall shapes also varies compared to the Cr $L_{2,3}$ edge at position (iii): this is in particular
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41 clear at position (ii), where Cr L_3 has a longer tail to the left of its main peak, suggesting that
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43 Cr^{3+} may also be present^{52,54}.
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49 **Substrate.** The spectra collected from the substrate contain signals from Fe and Cr in metallic
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51 form.
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54 A reasonable hypothesis based on the results of our ELNES analysis of the interface is that it
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56 is composed of Fe_2SiO_4 , Cr_2SiO_4 and small amounts of Cr^{3+} -rich oxides such as Cr_2O_3 or
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3 Cr^{3+} -bearing spinel, which have previously been reported as high temperature oxides of CrNi
4 steels⁵⁶. High-resolution TEM (HRTEM) images of the structure reveals that the interface is
5 crystalline (see also Figure S1 in the supporting information (SI)). A HRTEM image of the
6 substrate – coating structure with fast Fourier transform (FFT) patterns corresponding to
7 regions within each of the substrate, interface and the coating are depicted in Figure 3. The
8 crystalline nature of the substrate and the interface can be clearly seen in the image. However,
9 the FFT patterns obtained from the substrate and the interface regions are distinctly different,
10 indicating that the two regions have different crystal structures. Although not in a low-index
11 zone-axis orientation, the FFT pattern of the interface is compatible with a Fe_2SiO_4 structure
12 (see Figure S2 in the SI).

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The interface formation is expected to resemble the thermal oxidation of the substrate at low oxygen partial pressure (O_2 pp.) and elevated Si-access, whereby the O_2 pp. is expected to show a decrease from the outer region of the interface (e.g. position (ii) in Figure 2) to its inner region (e.g. position (iv) in Figure 2). Thus, the interface formation has been simulated by computation of the phase equilibrium of the substrate composition vs. O_2 pp. at 600 °C at elevated Si-level (for the computation a Si content of 2 wt.% has been assumed). The respective property diagram showing the phase equilibrium is shown in Figure 4. Clearly, the oxide-phase equilibrium is dominated by a Fe/Cr/Ni/Mn-rich spinel-structure oxide (M_3O_4), together with an Fe/Cr-rich corundum-structure oxide (M_2O_3) at high O_2 pp. and a stoichiometric Cr_2O_3 (corundum-structure) at low O_2 pp., which generally agrees with the medium temperature oxides that have been experimentally identified after the oxidation of CrNi steel⁵⁶. Neither of the previously discussed phases is enriched in Si. Si is entirely bound in form of quartz (SiO_2) over a broad range of O_2 pp. or a Fe-rich olivine-structure phase at medium O_2 pp. (i.e. fayalite). Overall, the equilibrium calculation supports the hypothesis of fayalite formation in the interfacial zone together with the formation of Cr_2O_3 directly at the substrate surface, where the lowest O_2 pp. is expected. Further, the calculated phase

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3 equilibrium is in agreement with the observation of Cr^{3+} in the outer region of the interfacial
4 zone, which may be bound in a spinel-type oxide where the highest O_2 pp. is expected. Since
5 no trace of Fe^{3+} was evident from the experiment, we propose that the formation of an outer
6 corundum-structure layer was suppressed by the low oxygen availability during the thermal
7 treatment. The formation of a thin, chemically bonded interfacial zone has been previously
8 linked to good adhesion between glasses and metals^{35,40}. Hence, the herein presented
9 formation of a silicate-rich interaction zone may be directly linked to the adhesion of the
10 coating, and thus prevent coating spallation and ensure an excellent performance and
11 mechanical durability of SOG based coatings in industrial applications⁵⁷. Further, the
12 formation of a silicate-rich interface zone has been related to an increased corrosion
13 resistance¹¹, and thus the herein observed interfacial zone may have a strong positive impact
14 on the corrosion behavior of the coating system. A detailed study of the performance of SOG
15 coatings on stainless steel substrates including a discussion of the impact of the herein
16 reported interface layer will be the content of following investigations.

34 35 **4 Summary and Conclusions**

36
37 In summary, we investigated the chemistry of the interface between AISI 316L and SOG
38 coating using STEM-EELS and HRTEM imaging. An interfacial region of ~ 10 nm thickness,
39 containing Si, O, Cr and Fe was detected. Analysis of the ELNES indicated these elements to
40 be in Fe^{2+} , Cr^{2+} (as well as, small amounts of Cr^{3+}) and $[\text{SiO}_4]^{4-}$ forms. HRTEM images of the
41 structure reveals that the interface is crystalline, with the FFT patterns matching a Fe_2SiO_4
42 (fayalite) -structure. The experimental results have been validated by thermodynamics
43 simulations and we suggest that thermal processing of the SOG leads to the formation of a
44 chemical interaction zone with the substrate which may generate excellent adhesion of the
45 coating.

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Tables

Table I: Chemical composition of the substrates (by Optical Emission Spectroscopy). In addition, traces (< 0.1 wt.%; > 0.01 wt.%) of P, Nb, V, W were also detected.

Element	Cr	Ni	Mo	Mn	Si	Cu	Co	N	C	Fe
Composition (wt.%)	16.8	10.4	2.07	0.92	0.47	0.41	0.21	0.048	0.019	bal.

Figure Captions

Figure 1: (a) HAADF STEM images of the coating on AISI 316L substrates in the cross-sectional geometry. (b) Relative composition profiles of O, Cr and Fe and the Si signal intensity across the interface extracted from EELS plotted together with the intensity profile of the HAADF STEM image along the line the EEL spectra were acquired from.

Figure 2: EELS spectra along a line across the coating – AISI 316L interface containing the (a) O K-, Cr L_{2,3}- and Fe L_{2,3}-edges and (b) Si L_{2,3}-edge.

Figure 3: HRTEM image of the coating – AISI 316L interface, with FFT patterns of selected regions from the coating, interface and the substrate.

Figure 4: Phase equilibrium vs. O₂ partial pressure diagram of the substrate composition at increased (2 wt.%) Si-level. The property diagram was computed with Thermo-Calc Software version 2017a³⁷, TCFE7.0.

Figures

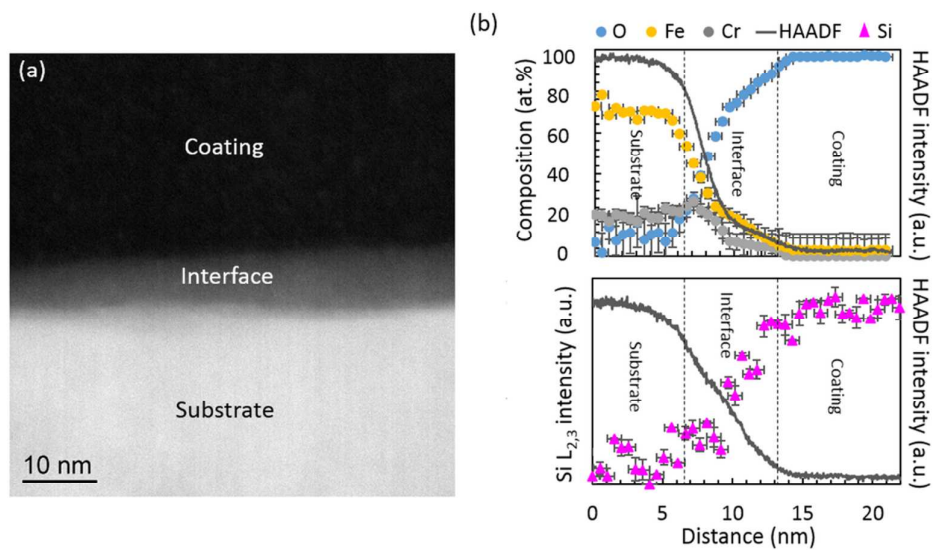


Figure 1

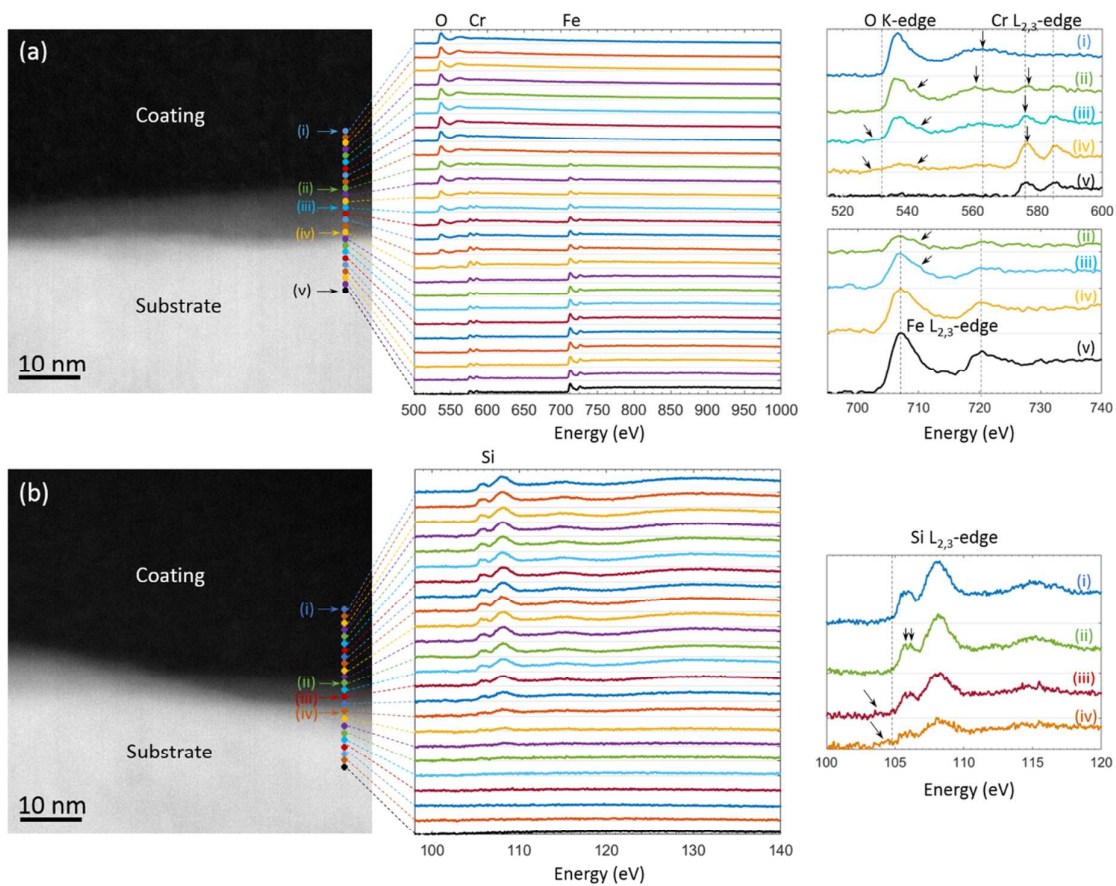
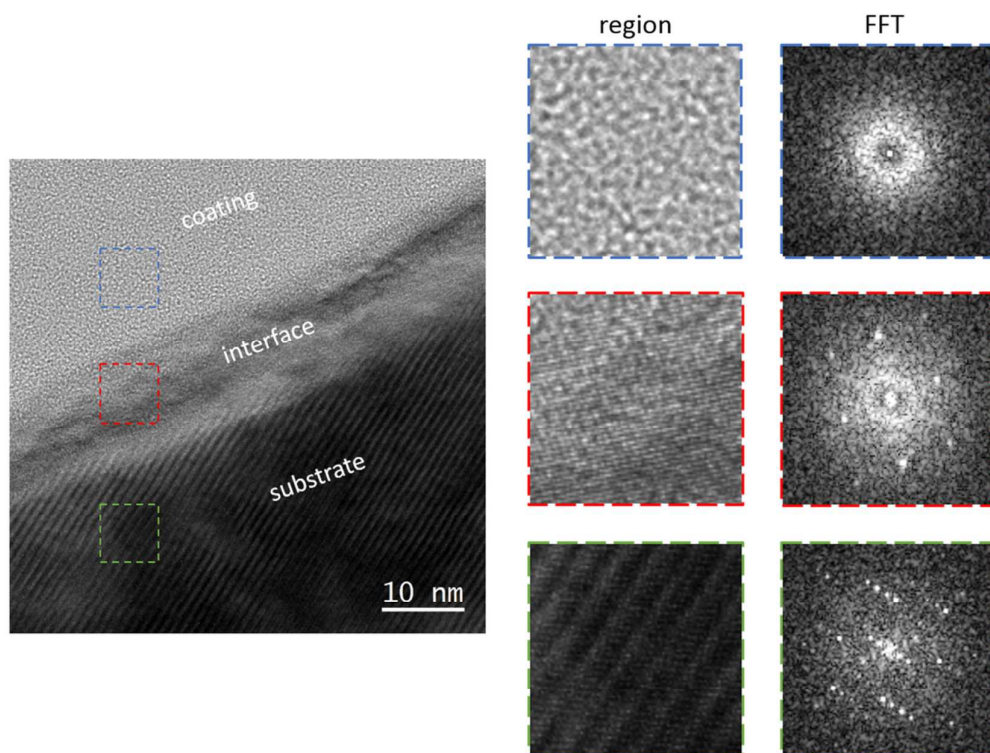


Figure 2



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Figure 3

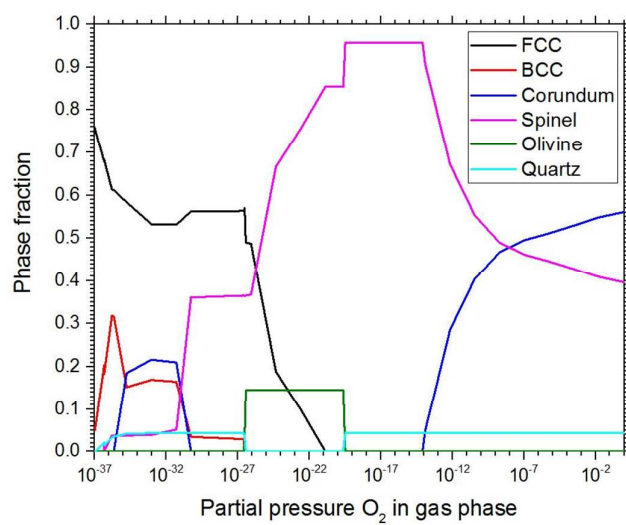


Figure 4